SPECIFICATION FOR APPROVAL

CUSTO	MER					
PART NA	ME	Multilayer Ceramic Chip Capacitors - SMD				
SPEC	PEC TS18 10uF 50V +/-10% X7R 1206 T&R RoHS*			oHS*		
DA DT NC						
PART NO	,					
DATE 2024-11-27		2024-11-27				
	CUSTOMER APPROVE					
[DRAWING					
	PRI	EPARED	CHECKED	APPROVED		

Suntan® Technology Company Limited
Unit H, 4/F., Dormind Industrial Building , 13 Yip Fung Street, Fanling, N. T., Hong Kong.

http://www.suntan.com.hk E-mail:info@suntan.com.hk

Tel: (852) 8202 8782 Fax: (852) 8208 6246

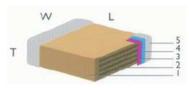
Feature

Miniature size, large capacitance, tape and reel packaging suitable for auto-placement

Standard size, various lead configuration

Dielectric Type	Class I	Class II			
Dielectric Material	Temperature Compensating	X7R (B)	Z5U(E)	Y5V(Y/F)	
Electrical Properties	The electrical properties is the most stable one and has little change with temperature, voltage and time.	X7R material has high dielectric constant, and its capacitance is higher than class I. These capacitors are classified as having a semi- stable T.C	Temperature characteristic is between that of X7R and Y5V. The capacitance is unstable and sensible to temperature and voltage.	Y5V material has highest dielectric constant. Its capacitance and dissipation is sensible to temperature and voltage.	
Application	Used in applications where low-losses and high-stability are required, such as filters, oscillators, and timing circuits so on.	Used over a wide temperature range, such in these kinds of circuits, DC-blocking, coupling, bypassing, frequency discriminating etc.	Ideally suited for bypassing and coupling application circuits operating with low DC bias in the environment approaching to room temperature.	temperature range in	
Available capacitance range	0.5pF~0.1uF	100pF22UF	1nF~10)uF	

Drawing



Size Code and Voltage VS Capacitance

Siza Codo	Dimension (mm)	Voltage	Available Capacitance Range	
Size Code	Dimension (mm)		X7R	
1206	06 L x W x T=3.2±0.2 x 1.6 ±0.2 x 1.6±0.2		106	

Reliability and Test Method for MLCC

Item	Technical Specification			Test Method and Remarks			
		within the specified tolerance.		Capacitance	Measuring Frequency	Measuring Voltage	
	Class I			≤1000pF	1MHZ±10%	1.0.0.01	
Capacitance				>1000 pF	1KHZ±10%	1.0±0.2V	
(C)		within the specified tolerance.		The capacitance should be pretreated before measured(only for classII).			
	ClassII			Measuring Frequency	Mea	Measuring Voltage	
				1KHZ±10%	B:1.0±0.2V	E/ F(Y) 0.3±0.2V	
	Class I	$\begin{array}{c} C_R{\geq}50 pF \\ DF{\leq}0.15\% \\ C_R{<}50 pF \\ DF{\leq}1.5[(150/C_R){}^{+}7]~X10^{-4} \end{array}.$		Capacitance	Measuring Frequency	Measuring Voltage	
				≤1000pF	1MHZ±10%	1.0±0.2V	
Dissipation				>1000 pF	1KHZ±10%	1.0±0.2 v	
Factor (DF)	Class II	В	DF ≤3.5%	Measuring Frequency: 1KHZ±10% Measuring Voltage: 1KHZ±10%		KHZ±10% HZ±10%	
		$\begin{array}{ c c c c }\hline E \\ Y/ \\ F \end{array} \qquad \begin{array}{ c c c c } & \leq 7.5\% \ (C_R \leq 0.1 uF) \\ \leq 10.0\% \\ & (1uF > C_R > 0.1 uF) \\ \leq 15\% \ (C_R \geq 1 uF) \end{array}$		Measuring Frequency: 1KHZ±10% Measuring Voltage: 0.3±0.2V			
Insulation Resistance	Class I	C≤10nF IR≥10000MΩ C>10nF R.C≥100 ΩF		Measuring Voltage: Rated Voltage Duration: 60±5s			
	Class II	C≤25nF IR≥4000MΩ C>25nF R.C≥100 ΩF					

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Item	Technical Specification		Test Method and Remarks	
	No breakdown or damage.		Between terminals: Measuring Voltage: Duration: 5±1s ClassI:300% Rated voltage ClassII:250% Rated voltage The charge/ discharge current is less than 50mA.	
Withstanding Voltage			Between terminals and body: Voltage: 2.5 times rated voltage Duration: 1~5s Small metallic ball method Small metallic balls with 1mm diameters shall be put in a vessel and the test capacitor shall be submerged except 2mm from the top of its component body and the terminals. The test voltage shall be applied between the short-circuited terminals and the metallic balls.	
Solder ability	Lead wire shall be at least 75% covered with a new solder coating.		The terminal of capacitor is dipping into a 25% rosin solution of ethanol and then into molten solder (Sn-2.5Ag-1Bi-0.5Cu) of 245±2°C for less than 3s. In both cases the depth of dipping is up to about 1.5~2mm from the terminal body.	
	Item	ΔC/C≤	Solder temperature: 265 ±3°C Duration: 6(+1,0)s	
B	Class I	$\pm 2.5\%$ or ± 0.25 pF	Immersed conditions: Inserted into the PC board (with t=1.6mm, hole=1.0mm diameter) Recovery: For class I, 4 to 24 hours of recovery under	
Resistance to Soldering Heat	В	±10%	the standard condition after test. Preconditioning (Class II): 1 hour of preconditioning	
	E / Y (F)	±20%	at 150(-10,+0) °C, followed by 48 ±4 hours of recovery under the standard condition.	
	No significant abnormality in appearance.		Recovery (Class II): 48 ±4 hours of recovery under the standard condition after test.	
	No significant abnormality in appearance.		Temperature	
	Capacitance Change	:	X7R	
	Class I: $\leq \pm 3\%$ or ± 0.3 pF Whichever is larger. Class II: B: $\leq \pm 12.5\%$ E / F(Y): $\leq \pm 30\%$		125(-0,+3)°C	
			Applied voltage: 1.5 times rated voltage. The charge/ discharge current is less than 50mA. Duration: 1000 (-0, +48) hours Recovery Time: Class I Dielectric: 24 ±2 hours Class II Dielectric: 48 ±4 hours	
High Temperature Loading Test	Dissipation Factor: Class I: Not more than twice of initial value. Class II: B: $\leq 5.0\%$ E / F(Y): $\leq 12.5\%$ ($C_R \leq 0.1 uF$) $\leq 15.0\%$ ($1uF > C_R > 0.1 uF$) $\leq 17.5\%$ ($C_R \geq 1 uF$)			
	Insulation Resistance $\geq 500 \text{M}\Omega$ or 25 Ω . Whichever is smalle	F		
Solvent Resistance	No defects or abnormalities in appearance and legible marking.		Solvent temperature: 23±5°C put the sample into solvent 1 Min, and then take it out and brush sample's notation area 10 times with pledget, repeat 3 times.	

^{*}Note on standard condition: "standard condition "referred to herein should be defined as follows: 5 to 35°C of temperature, 45 to 75% of relative humidity, and 86 to 106kPa of atmospheric pressure.

* When there are questions concerning measurement results:

In order to provide correlation data, the test should be conducted under a condition of 25 degrees plus/minus 1 centigrade of temperature, 48% through 52% of relative humidity and 86 through 106 kPa of atmospheric pressure.

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